

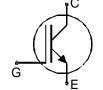
IGBT³ Chip

FEATURES:

- 1700V Trench + Field Stop technology
- low turn-off losses
- short tail current
- positive temperature coefficient
- · easy paralleling

This chip is used for:

power module



Applications:

• drives

| Chip Type | V _{CE} | I _{Cn} | Die Size | Package | Ordering Code |
|---------------|-----------------|-----------------|-------------------------------|--------------|-----------------------|
| SIGC186T170R3 | 1700V | 150A | 13.63 x 13.63 mm ² | sawn on foil | Q67050- A4148-A001 |

MECHANICAL PARAMETER:

| Raster size | 13.63 x 13.63 | | |
|---------------------------------|---|-----------------|--|
| Emitter pad size | 8 x (5.62 x 2.71) | | |
| Gate pad size | 1.12 x 1.12 | | |
| Area total / active | 185.8 / 149.7 | mm ² | |
| Thickness | 190 | μm | |
| Wafer size | 150 | mm | |
| Flat position | 90 | grd | |
| Max.possible chips per wafer | 69 pcs | | |
| Passivation frontside | Photoimide | | |
| Emitter metalization | 3200 nm AlSiCu | | |
| Collector metalization | 1400 nm Ni Ag -system suitable for epoxy and soft solder die bonding | | |
| Die bond | electrically conductive glue or solder | | |
| Wire bond | Al, <500μm | | |
| Reject Ink Dot Size | ∅ 0.65mm ; max 1.2mm | | |
| Recommended Storage Environment | store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C | | |



MAXIMUM RATINGS:

| Parameter | Symbol | Value | Unit |
|---|--------------------|------------------|------|
| Collector-emitter voltage, T _j =25 °C | V _{CE} | 1700 | V |
| DC collector current, limited by T _{jmax} | I _C | 1) | А |
| Pulsed collector current, t _p limited by T _{jmax} | I _{cpuls} | 450 | Α |
| Gate emitter voltage | V _{GE} | ±20 | V |
| Operating junction and storage temperature | T_j , T_{stg} | -55 + 150 | °C |

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

| Parameter | Symbol | Conditions | Value | | | Unit |
|--------------------------------------|----------------------|--|-------|------|------|------|
| Turumeter | | | min. | typ. | max. | |
| Collector-emitter breakdown voltage | V _{(BR)CES} | V_{GE} =0 V , I_{C} = 4 mA | 1700 | | | |
| Collector-emitter saturation voltage | V _{CE(sat)} | V _{GE} =15V, I _C =150A | 1.6 | 2 | 2.4 | V |
| Gate-emitter threshold voltage | V _{GE(th)} | I _C =6mA , V _{GE} =V _{CE} | 5.2 | 5.8 | 6.4 | |
| Zero gate voltage collector current | I _{CES} | V _{CE} =1700V , V _{GE} =0V | | | 8.2 | μA |
| Gate-emitter leakage current | I _{GES} | V _{CE} =0V , V _{GE} =20V | | | 600 | nA |
| Integrated gate resistor | R _{Gint} | | | 5 | | Ω |

ELECTRICAL CHARACTERISTICS (tested at component):

| Parameter | Symbol Conditions | Value | | | Unit | |
|------------------------------|-------------------|-----------------------|------|-------|------|------|
| raiailietei | Symbol | Conditions | min. | typ. | max. | Onne |
| Input capacitance | Ciss | V _{CE} =25V, | | 13196 | | pF |
| Output capacitance | Coss | $V_{GE}=0V$, | | 549 | | |
| Reverse transfer capacitance | Crss | f=1MHz | | 438 | | |

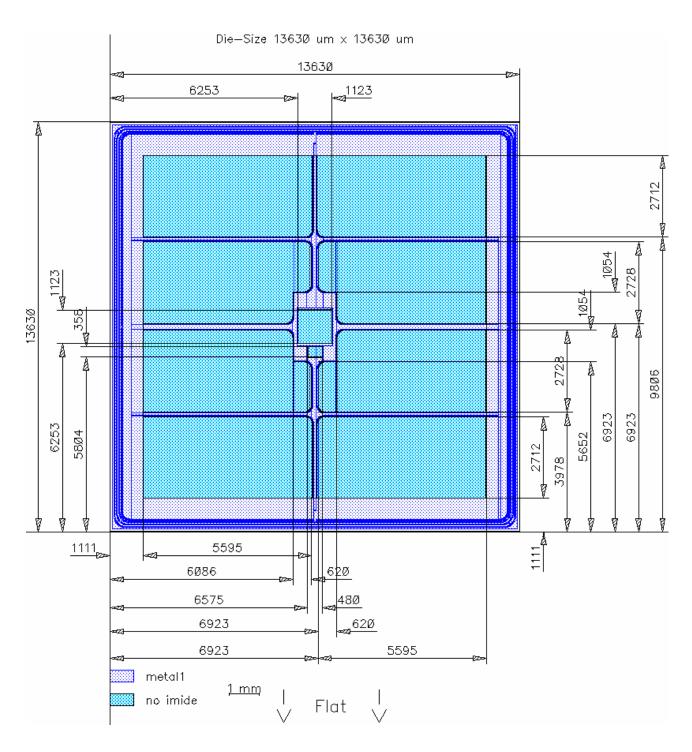
SWITCHING CHARACTERISTICS (tested at component), Inductive Load

| Parameter | Symbol | Conditions 1) | Value | | | Unit |
|---------------------|----------------|--|-------|-------|------|------|
| - arameter | | | min. | typ. | max. | Onne |
| Turn-on delay time | $t_{d(on)}$ | T _j =125°C | | 0.30 | | μs |
| Rise time | t _r | V _{CC} =900V, I _C =150A, V _{GE} =-15/15V, | | 0.066 | | |
| Turn-off delay time | $t_{d(off)}$ | $V_{\text{GE}} = -15/15 \text{V},$ | | 1 | | |
| Fall time | t_{f} | $R_{\rm G}$ = 9.1 Ω | | 0.30 | | |

¹⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





FURTHER ELECTRICAL CHARACTERISTICS:

| This chip data sheet refers to the device data sheet | tbd | | | | | |
|---|-----|--|--|--|--|--|
| | | | | | | |
| DESCRIPTION: | | | | | | |
| AQL 0,65 for visual inspection according to failure catalog | | | | | | |
| Electrostatic Discharge Sensitive Device according to MIL-STD 883 | | | | | | |
| Test-Normen Villach/Prüffeld | | | | | | |

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